



Graphene Standardization: Key Success Factor for Graphene Industrialization

Graphene 2018 – Industrial Forum, June 28, 2018



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IEC/TC 113: NANOTECHNOLOGY FOR ELECTROTECHNICAL PRODUCTS AND SYSTEMS





1. The Need for & Benefits of Standardization

- 2. The IEC Standardization Process
- 3. Conclusions



The generic value adding chain for graphene-based products:



How to ensure CONSISTENT QUALITY ?

IEC 1. The Need & Benefits of Standardization

- The Performance and reliability is "MADE", not tested, via
- Key Control Characteristics KCCs
- Details Specification (DS) & Blank Detail Specification (BDS)





Detailed background information in 2 books, and in the Standard ISO 9001:2015 for Quality Management Systems





Case Study:

Transition 200mm → 300mm wafers Microelectronics

- □ Previous transitions (e.g. 150mm \rightarrow 200mm): Disastrous!
- □ 200mm \rightarrow 300mm:
 - Anticipiative standardization in I300I consortium
 - about 50 SEMI standards created BEFORE the transition was implemented
- □ Result:
 - Smooth transition
 - First production lot on 300mm had in 200mm a <u>higher yield than</u> the mature 200mm production
 - Cost savings estimated to be > 10 billion \$



Survey by B. Weiss from SEMI showed: Cycle time reduced



W. Bergholz, B. Weiss and C. Lee, "Benefits of Standardization in the Microelectronics Industry and its implications for Nanotechnology and other Innovative Industries", in "International Standardization as a Strategic Tool", Commended Papers from the IEC Centenary Challenge 2006 Publication, p35 - 50





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Concept of the "Blank Detail Specification" (BDS) and Key Control Characteristics (KCCs) developed in IEC TC 113 is core to the QUALITY MANAGEMENT BASED STRATEGY

- Standardized format for the specification for the KCCs of the material / equipment / ...
- BDS: No numbers for KCCs, DS with number, Sectional Detail
 Specification with some number
- Recommendation for standardized characterization methods to determine the KCCs

2. The IEC Standardization Process Blank Detail Specification (BDS) – excerpt for Graphene

Table 4 – Format for electrical key control characteristics

KCC No	ксс	Specification	Measurement method	F	P	D
4.1			IEC/TS 62607-06-04			
	Sheetresistance	Nominal[] ± Tolerance[]Ω/sg	IEC/TS 62607-06-08	~		12
			IEC/TS 62607-06-09			•
			IEC/TS 62607-06-10			
4.2	Sheet conductance	Nominal[]±Tolerance[]S/sg	IEC/TS 62607-06-04	✓		√ ²
4.3	Conductivity	Nominal[] ± Tolerance[] S/m	IEC/TS 62607-06-01		✓1	
4.4	Field effect carrier mobility	Nominal[] ± Tolerance[] cm²/Vs		<		
4.5	Hall carrier mobility	Nominal[] ± Tolerance[] cm²/Vs		<		
4.6	Work function	Nominal[] ± Tolerance[] meV		✓		

Note

1) Measured on pellets

2) Measured on films solidified according to suppliers specification



BDS standards and KCC measurement standards





Moving towards industry oriented standardization



Standardization supports cooperation between the EU-Flagship and other EU projects like "Polygraph (FP7)", "Gladiator (FP7)", "GRACE" (Euramet EMPIR) as well as national funded projects.



2. The IEC Standardization Process Example: sheet resistance, THz-TDS (IEC/TS 62607-6-10)

Measurement configurations:



Quality assessment of terahertz time-domain spectroscopy transmission and reflection modes for graphene conductivity mapping ¹³ David M. A. Mackenzie^{1,*}, Patrick R. Whelan¹, Peter Bøggild¹, Peter Uhd Jepsen², Albert Redo-Sanchez³, David Etayo³, Norbert Fabricius⁴, Dirch Hjorth Petersen¹



Current status of selected IEC graphene standardization projects

	62565- 03-05	62607- 06-06	62607- 06-08	62607- 06-09	62607- 06-10	62607- 06-11	62607- 06-12	62876- 03-01
Stage	BDS: Graphene powder	KCC: strain uniformity parameter	KCC: sheet resistance	KCC: sheet resistance	KCC: sheet resistance	KCC: defect density	KCC: number of layers	Reliability
		Raman	4 point probe	Eddy current	THz-TDS	Raman	Raman, optical reflection	T, ΔT, RH
PWI								
NP								
CD								
DTS								
TS								



Standardization landscape "Graphene and other 2D-Materials"





Standardization landscape "Graphene and other 2D-Materials"

If you want to know more details about:

- □ Standardization
- Certification of Graphene Products and the manufacturing process

Standardization and certification seminar

- Co-organized by IGCC (International Graphene Products Certificate Center), Phantoms Foundation and ISC (International Standards Consulting GmbH & Co KG)
- □ **Date**: Thursday June 28, 2018 15:00 to 19:00
- □ Location: Conference room 2 (Conference level







Update on ISO meeting(s), IEC/TC 113 & ISO/TC 229 work

- <u>Meeting schedule</u>:
 - Last: Ottawa, May 2018, joint with ISO/TC 229
 - Next: Busan, October 2018, co-located with IEC General Meeting
 - Next Meeting with ISO: Sidney, Australia, around May, exact date tbd





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